

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination JEONG ET AL.	
		Examiner Andrew Lee	Art Unit 2616	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2004/0249975	12-2004	Tuck et al.	709/245
*	B US-2004/0095943	05-2004	Korotin, Dmitry O.	370/401
*	C US-2002/0052972	05-2002	Yim, Ui-Suk	709/245
*	D US-2002/0019933	02-2002	Friedman et al.	713/160
*	E US-2005/0232254	10-2005	Korner, Ulrich	370/360
*	F US-2003/0016624	01-2003	Bare, Ballard C.	370/217
*	G US-2003/0140124	07-2003	Burns, David A.	709/220
*	H US-7,093,030	08-2006	Henry et al.	709/250
*	I US-6,633,565	10-2003	Bronstein et al.	370/392
*	J US-6,434,627	08-2002	Millet et al.	709/245
*	K US-6,314,531	11-2001	Kram, Paul Regis	714/38
*	L US-6,552,997	04-2003	Inoue et al.	370/217
*	M US-6,870,852	03-2005	Lawitzke, John H.	370/401

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
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NON-PATENT DOCUMENTS

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